MAPS Rec'd PCT/PTO 30 DEC 2005

Sheet <u>1</u> of <u>1</u>

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 126503		New	APPLICATION NO. New U.S. National Stage of PCT/FR2004/001699		
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(Use several sheets if necessary)				APPLICANTS Hubert GRANGE et al.					
				FILING DATE December 30, 2005					
U.S. PATENT DOCUMENTS									
EXAMINER INITIAL		DOCUMENT NUMBER	DATE		NAM	NAME		SUB CLASS	
/AWO/	1	5,750,420	05/12/1998		Bono et al.		30000000	xx000000000000000000000000000000000000	
/AWO/	2	6,004,832	12/21/1999		Haller et al.		*************		
/AWO/	3	5,824,608	10/20/1998		Gotoh et al.		100000000000000000000000000000000000000	000000000000000000000000000000000000000	
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FOREIGN PATENT DOCUMENTS									
		DOCUMENT NUMBER		DATE	COUNTRY		CLASS	SUB CLASS	
/AWO/	5	EP 0 456 029 A1	11/13/1991		Europe		***************************************	200000000000000000000000000000000000000	
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		OTHER DOCUMENTS (Inc	Fitle, Date, Pertinent Page	es, etc.)	· !				
/AWO/	6	Alley et al., "The Effect of Release-Etch Processing on Surface Microstructure Stiction," Solid-State Sensor and Actuator Workshop, 5 th Technical Digest, IEEE Hilton, pp. 202-207, 1992							
A DESCRIPTION OF THE PROPERTY		·							
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EXAMINER /Allan Olsen/					DATE CONSIDERED 03/31/2007				
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									

Date: December 30, 2005